IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No. : 10/815,504 Confirmation No. : 8217 Applicant(s) : Satoru WAKAO Filed : March 31, 2004 Title : IMAGE VERIFICATION APPARATUS AND IMAGE VERIFICATION METHOD Art Unit : 2624 Examiner : Seved H. AZARIAN Docket No. : 1232-5362 . 27123 Customer No. INFORMATION DISCLOSURE STATEMENT Mail Stop Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 Sir: Pursuant to Rule 56, applicant hereby calls the attention of the Patent Office to the references listed on the attached Form PTO 1449. Copy(ies) of these references: Foreign Patent Applications, Foreign Patents and/or Other Non-Patent Documents are attached (Copies of cited U.S. Patents/Publications are not provided). Were filed in related application U.S. Serial No(s) , respectively. This document is being filed within three (3) months of the filing date of the application A check for the requisite fee of \$180 is enclosed. This document is being concurrently filed with the above-identified application This document is being concurrently filed with an Request for Continued Examination (RCE) This document is being filed prior to a first Office Action This document is accompanied by a Search Report/Communication cited in a corresponding PCT or foreign counterpart application. X The Commissioner is hereby authorized to charge any additional fees which may be required for this Information Disclosure Statement, or credit any overpayment to Deposit Account No. 13-4500, Order No. 1232-5362. A DUPLICATE COPY OF THIS SHEET IS ATTACHED. Respectfully submitted, MORGAN & FINNEGAN, L.L.P. Dated: July 24, 2007 Steven F. Meyer Registration No. 35,613 Correspondence Address: Address Associated With Customer Number: 27123 (212) 415-8700 Telephone

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INFORMATION DISCLOSURE CITATION

Filing Date: March 31, 2004 U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Publication Date	Name	Class	Sub-Class	Filing Date
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Papers, etc.)					

Examiner		Date Considered		
EXAMINER:	Initial if reference considered, whether or not citation is in conformance with MPEP §609.			
	Draw line through citation if not in conformance and not considered.			
	Include copy of this form with next communication to Applicant.			